

VLSI DESIGN

Module – I

08 Hours

Introduction: Historical Perspective, VLSI Design Methodologies, VLSI Design Flow, Design Hierarchy, Concept of Regularity, Modularity and Locality, VLSI Design Styles, Computer-Aided Design Technology.

Fabrication of MOSFETs: Introduction, Fabrication Processes Flow – Basic Concepts, The CMOS n-Well Process, Layout Design Rules, Stick Diagrams, Full-Customs Mask Layout Design.

MOS Transistor: The Metal Oxide Semiconductor (MOS) Structure, The MOS System under External Bias, Structure and Operation of MOS Transistor (MOSFET), MOSFET Current-Voltage Characteristics, MOSFET Scaling and Small-Geometry Effects, MOSFET Capacitance.

(Chapter 1 to 3 of Text Book 1 and for Stick Diagram Text Book 2)

Module – II

14 Hours

MOS Inverters – Static Characteristics: Introduction, Resistive-Load Inverters, Inverters with n-Type MOSFET Load, CMOS Inverter.

MOS Inverters – Switching Characteristics and Interconnect Effects: Introduction, Delay-Time Definitions, Calculation of Delay-Times, Inverter Design with Delay Constraints, Estimation of Interconnect Parasitics, Calculation of Interconnect Delay, Switching Power Dissipation of CMOS Inverters.

Combinational MOS Logic Circuits: Introduction, MOS Logic Circuits with Depletion nMOS Loads, CMOS Logic Circuits, Complex Logic Circuits, CMOS Transmission Gates (Pass Gates).

(Chapter 5 to 7 of Text Book 1)

Module – III

18 Hours

Sequential MOS Logic Circuits: Introduction, Behaviour of Bistable Elements, SR Latch Circuits, Clocked Latch and Flip-Flop Circuits, CMOS D-Latch and Edge-Triggered Flip-Flop.

Dynamic Logic Circuits: Introduction, Basic Principles of Pass Transistor Circuits, Voltage Bootstrapping, Synchronous Dynamic Circuit Techniques, Dynamic CMOS Circuit Techniques, High Performance Dynamic CMOS Circuits.

Semiconductor Memories: Introduction, Dynamic Random Access Memory (DRAM), Static Random Access Memory (SRAM), Non-volatile Memory, Flash Memory.

Design for Testability: Introduction, Fault Types and Models, Ad Hoc Testable Design Techniques, Scan-Based Techniques, Built-In Self-Test (BIST) Techniques, Current Monitoring I_{DDQ} Test.

Text Books:

1. Sung-Mo Kang and Yusuf Leblebici, *CMOS Digital Integrated Circuits: Analysis and Design*, 3rd Edn., Tata McGraw-Hill Publishing Company Limited, 2003.
2. K. Eshraghian and N.H.E. Weste, *Principles of CMOS VLSI Design – a Systems Perspective*, 2nd Edn., Addison Wesley, 1993.

Reference Books:

1. Jan M. Rabaey, Anantha Chandrakasan, Borivoje Nikolic, *Digital Integrated Circuits – A Design Perspective*, 2nd Edn., PHI.
2. Wayne Wolf, *Modern VLSI Design System – on – Chip Design*, 3rd Edn., PHI
3. Debaprasad Das, *VLSI Design*, Oxford University Press, New Delhi, 2010.
4. John P. Uyemura, *CMOS Logic Circuit Design*, Springer (Kluwer Academic Publishers), 2001.
5. Ken Martin, *Digital Integrated Circuit Design*, Oxford University Press, 2000.